



FORM PTO 1449	SERIAL NO. 10/035,025	CASE NO. 10544/169
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE December 28, 2001	GROUP ART UNIT 2882
(use several sheets if necessary)		APPLICANT(S): Vladimir V. Protopov

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
EMJ	A1	2,853,617	09/23/1958	Berreman		
EMJ	A2	3,032,656	05/1/1962	Hosemann et al.		
EMJ	A3	3,409,372	11/5/1968	Ricken		
EMJ	A4	3,614,425	10/19/1971	Yoshimatsu		
EMJ	A5	3,899,253	08/12/1975	Overhoff		
EMJ	A6	3,927,319	12/16/1975	Wittry		
EMJ	A7	4,274,000	06/16/1981	Goebel		
EMJ	A8	4,364,122	12/14/1982	Wolfel et al.		
EMJ	A9	4,461,018	07/17/1984	Ice et al.		
EMJ	A10	4,525,853	06/25/1985	Keem et al.		
EMJ	A11	4,547,801	10/15/1985	Haisma et al.		
EMJ	A12	4,599,741	07/08/1986	Wittry		
EMJ	A13	4,611,341	09/09/1986	Brody		
EMJ	A14	4,643,951	02/17/1987	Keem et al.		
EMJ	A15	4,675,889	06/23/1987	Wood et al.		
EMJ	A16	4,684,565	08/04/1987	Abeles et al.		
EMJ	A17	4,693,933	09/15/1987	Keem et al.		
EMJ	A18	4,716,083	12/29/1987	Eichen et al.		
EMJ	A19	4,717,632	01/05/1988	Keem et al.		
EMJ	A20	4,724,169	02/09/1988	Keem et al.		
EMJ	A21	4,727,000	02/23/1988	Ovshinsky et al.		
EMJ	A22	4,741,620	05/03/1988	Wickramasinghe		
EMJ	A23	4,777,090	10/11/1988	Ovshinsky et al.		
EMJ	A24	4,783,374	11/08/1988	Custer et al.		
EMJ	A25	4,785,470	11/15/1988	Wood et al.		
EMJ	A26	4,867,785	09/19/1989	Keem et al.		
EMJ	A27	4,873,439	10/10/1989	Hagelstein et al.		
EMJ	A28	4,884,697	12/05/1989	Takacs et al.		
EMJ	A29	4,890,310	12/26/1989	Umetani et al.		
EMJ	A30	4,916,721	04/10/1990	Carr et al.		
EMJ	A31	4,928,294	05/22/1990	Beard, Jr. et al.		
EMJ	A32	4,953,188	08/28/1990	Siegel et al.		
EMJ	A33	4,969,175	11/06/1990	Nelson et al.		
EMJ	A34	5,016,267	01/25/2000	Wilkins		
EMJ	A35	5,082,621	01/21/1992	Wood		
EMJ	A36	5,162,872	11/10/1992	Vanasse		
EMJ	A37	5,167,912	12/01/1992	Wood		

EXAMINER <i>E. J. Hemmell</i>	DATE CONSIDERED 1/22/03
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EMJ	A38	5,173,928	12/22/1992	Momose et al.		
EMJ	A39	5,245,648	09/14/1993	Kinney et al.		
EMJ	A40	5,259,013	11/02/1993	Kuriyama et al.		
EMJ	A41	5,319,694	06/07/1994	Ingal et al.		
EMJ	A42	5,384,817	01/24/1995	Crowther et al.		
EMJ	A43	5,406,609	04/11/1995	Arai et al.		
EMJ	A44	5,408,512	04/18/1995	Kuwabara et al.		
EMJ	A45	5,450,201	09/12/1995	Katzir et al.		
EMJ	A46	5,458,084	10/17/1995	Thorne et al.		
EMJ	A47	5,551,587	09/03/1996	Keppel et al.		
EMJ	A48	5,579,363	11/26/1996	Ingal et al.		
EMJ	A49	5,592,338	01/7/1997	Citterio		
EMJ	A50	5,638,175	06/10/1997	Brunfeld et al.		
EMJ	A51	5,646,976	07/08/1997	Gutman		
EMJ	A52	5,684,852	11/4/1997	Tomie		
EMJ	A53	5,715,291	02/03/1998	Momose		
EMJ	A54	5,732,120	03/24/1998	Shoji et al.		
EMJ	A55	5,757,882	05/26/1998	Gutman		
EMJ	A56	5,784,162	07/21/1998	Cabib et al.		
EMJ	A57	5,799,056	08/25/1998	Gutman		
EMJ	A58	5,802,137	09/01/1998	Wilkins		
EMJ	A59	5,850,425	12/15/1998	Wilkins		
EMJ	A60	5,878,108	03/02/1999	Baba et al.		
EMJ	A61	5,881,126	03/09/1999	Momose		
EMJ	A62	5,898,752	04/27/1999	Van Der Wal		
EMJ	A63	5,914,997	06/22/1999	Van Egeraat		
EMJ	A64	5,930,325	07/27/1999	Momose		
EMJ	A65	5,936,255	08/10/1999	Nakanishi et al.		
EMJ	A66	5,987,095	11/16/1999	Chapman et al.		
EMJ	A67	6,014,423	01/11/2000	Gutman et al.		
EMJ	A68	6,018,564	01/25/2000	Wilkins		
EMJ	A69	6,018,565	01/25/2000	Ergun et al.		
EMJ	A70	6,021,223	02/01/2000	Toyoda et al.		
EMJ	A71	6,041,099	03/21/2000	Gutman et al.		
EMJ	A72	6,069,933	05/30/2000	Schultz		
EMJ	A73	6,069,934	05/30/2000	Verman et al.		
EMJ	A74	6,144,719	11/7/2000	Hasegawa et al.		
EMJ	A75	6,195,410 B1	02/27/2001	Cash, Jr.		
EMJ	A76	6,212,254 B1	04/03/2001	Wilkins		

EXAMINER <i>Elizabeth J. Small</i>	DATE CONSIDERED <i>1/22/03</i>
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EMJ	A77	6,226,349 B1	05/01/2001	Schuster et al.	—	
EMJ	A78	6,226,353 B1	05/01/2001	Wilkins et al.	—	
EMJ	A79	6,295,130 B1	09/25/2001	Sun et al.	—	
EMJ	A80	6,330,301 B1	12/11/2001	Jiang	—	
EMJ	A81	6,389,100 B1	05/14/2002	Verman et al.	—	
EMJ	A82	6,421,417 B1	07/16/2002	Jiang et al.	—	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES	NO
EMJ	A83	2 137 453 A	10/03/1984	U.K.	—		X
EMJ	A84	2 203 620 A	10/19/1988	U.K.	—		X
EMJ	A85	WO 88/08530	11/03/1988	WIPO	—		X
EMJ	A86	0 20444088	11/1/1991	Japan	—	X	
EMJ	A87	0 274 155 B1	03/18/1992	EP	—		X
EMJ	A88	0 623 817 A1	11/09/1994	EP	—		X
EMJ	A89	WO 95/05725	02/23/1995	WIPO			X

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
EMJ	A90	Wayne T. Sproull, "X-Rays in Practice", published by McGraw-Hill Book Company, 1946, pp. 391-409.
EMJ	A91	"X-Ray Diffractometer for Thin Films", IBM Technical Disclosure Bulletin, published by IBM, May 1969, pp. 1728-1729.
EMJ	A92	"Use of Lithography to Subject Crystal Wafers to a Controlled Elastic or Plastic Strain", IBM Technical Disclosure Bulletin, published by IBM, December 1985, pp. 3166-3167.
EMJ	A93	Leonid V. Araroff, "X-Ray Spectroscopy", Published by McGraw-Hill Book Company, 1974, pp. 54-67 and 101-106.
EMJ	A94	"Measuring Tensions in Thin Film", IBM Technical Disclosure Bulletin, published by IBM, October 1974, pp. 1394-1395.
EMJ	A95	"Device for Automatic Recording of X-Ray Spectra", IBM Technical Disclosure Bulletin, published by IBM, July 1980, pp. 833-834.
EMJ	A96	K.M. Podurets et al., "Neutron Radiography with Refraction Constant" Physics B Vols. 156 & 157, 1989, p. 691.
EMJ	A97	English language abstract regarding Japanese published application No. 61-256243 that was published November 13, 1986, while the date of publication of the English language abstract is unknown it is believed to have occurred prior to March 1, 2000.

EXAMINER <i>Elizabeth L. Lamm</i>	DATE CONSIDERED 1/22/03
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EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
EMJ	A98	English language abstract regarding Japanese published application No. 63-53456 that was published March 7, 1988, while the date of publication of the English language abstract is unknown it is believed to have occurred prior to March 1, 2000.
EMJ	A99	English language abstract regarding Japanese published application No. 1-187440 that was published July 26, 1989, while the date of publication of the English language abstract is unknown it is believed to have occurred prior to March 1, 2000.
EMJ	A100	Pending U.S. Patent Application Serial No. 09/797,498, filed March 1, 2001 by Martyhov et al.
EMJ	A101	V.V. Protopopov et al., "X-Ray Multilayer Mirrors With An Extended Angular Range," Optics Communications, Vol. 158, December 15, 1998, pp. 127-140.
EMJ	A102	V.V. Protopopov, "On the Possibility of X-Ray Refractive Radiography Using Multilayer Mirrors With Resonant Absorption," Optics Communications, Vol. 174, January 15, 2000, pp. 13-18.
EMJ	A103	Richard Fitzgerald, "Phase-Sensitive X-Ray Imaging," Physics Today, July 2000, pp. 23-26.
EMJ	A104	V.V. Protopopov et al., "Observation of X-Ray Refraction Contrast Using Multilayer Mirrors With Resonant Absorption," Optics Communications, Dispatch 17, August 2000, pp. 1-6.
EMJ	A105	INSPEC Abstract Number A1999-18-8760J-017, B1999-09-7510P-044, available on or before February 8, 2001, 2 pages, regarding "Mammography Imaging Studies Using A Laue Crystal Analyzer," by Chapman et al., Review of Scientific Instruments Conference, Vol. 67, No. 9, September 1996, p. 5.
EMJ	A106	INSPEC Abstract Number A9514-0785-044, B9508-7450-005, available on or before February 8, 2001, 2 pages, regarding "Backscattering Analyzer Geometry As A Straightforward and Precise Method for Monochromator Characterization at Third-Generation Synchrotron-Radiation Sources," by Snigirev et al., Review of Scientific Instruments, Vol. 66, No. 2, Pt. 2, February, 1995, p. 2228.
EMJ	A107	INSPEC Abstract Number A9502-6110D-005, available on or before February 8, 2001, 2 pages, regarding "The Resolution Function of a Triple-Crystal Diffractometer for High-Energy Synchrotron Radiation in Nondispersive Laue Geometry," by Neumann et al., Journal of Applied Crystallography, Vol. 27, Pt. 6, December 1, 1994, pp. 1030-1038.
EMJ	A108	INSPEC Abstract Number A9210-0785-020, available on or before February 8, 2001, 2 pages, regarding "Polarization Analysis in Magnetic X-Ray Scattering Using 45 Degrees Linearly Polarized X-Ray Incident Beam," by Mori et al., Review of Scientific Instruments, Vol. 63, No. 1, Pt. 11B, January, 1992, p. 1176.
EMJ	A109	INSPEC Abstract Number A9209-0785-045, available on or before February 8, 2001, 2 pages, regarding "Focusing Monochromator for High Energy Synchrotron Radiation," by Suortti, P., Review of Scientific Instruments, Vol. 63, No. 1, Pt. 11B, January, 1992, pp. 942-945.
EMJ	A110	INSPEC Abstract Number A83081373, available on or before February 8, 2001, 2 pages, regarding "Use of a Position Sensitive Detector for Data Acquisition of Synchrotron X-Ray Diffraction from Absorbed Gas Monolayers on Graphite," by Bohr et al., Nuclear Instruments and Methods in Physics Research, Vol. 208, Nos. 1-3, April 15, 1983, pp. 555-558.
EMJ	A111	INSPEC Abstract Number A9223-0785-008, available on or before February 8, 2001, 1 page, regarding "Refraction Contrast in X-Ray Introspecty," by Somenkov et al., Zhurnal Tekhnicheskoi Fiziki, Vol. 61, No. 11, November, 1991, pp. 1309-1311.

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